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Murata Electronics North America ZRB18AC81A106KE01L

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Only Reflow Soldering Chip Monolithic Ceramic Capacitor on Interposer for General ZRB18AC81A106KE01_ (0603, X6S, 10uF, DC10V)



_: packaging code

Reference Sheet

1.Scope

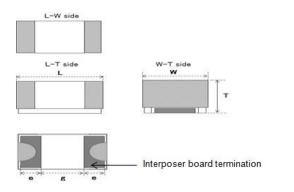
This product specification is applied to Chip Monolithic Ceramic Capacitor on Interposer used for General Electronic equipment.

This product is applied for Only Reflow Soldering.

2.MURATA Part NO. System



3. Type & Dimensions



				(Unit:mm)
(1)-1 L	(1)-2 W	(2) T	е	g
1.6±0.2	0.8±0.2	1.0±0.2	0.2 to 0.65	0.6 min.

4.Rated value

(3) Temperature Characteristics (Public STD Code):X6S(EIA)		(4) DC Rated	(5) Nominal	(6) Capacitance	Specifications and Test Methods
Temp. coeff or Cap. Change	Temp. Range (Ref.Temp.)	Voltage	Capacitance	Tolerance	(Operating Temp. Range)
-22 to 22 %	-55 to 105 °C (25 °C)	10 Vdc	10 uF	±10 %	-55 to 105 °C

5.Package

mark	(8) Packaging	Packaging Unit
L	∳180mm Reel EMBOSSED W8P4	3000 pcs./Reel

Product specifications in this catalog are as of May.25,2014,and are subject to change or obsolescence without notice. Please consult the approval sheet before ordering. Please read rating and !Cautions first.



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SPECIFICATIONS AND TEST METHODS

No	Item	Specification	Test Method
	Operating	C8:-55°C to 105°C	Standard Temperature : 25°C
	Temperature Range	D7 : -55°C to 125°C	
2	Rated Voltage	See the previous pages.	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{P-P} or V ^{Q-P} , whichever is larger, should be maintained within the rated voltage range.
3	Appearance	No defects or abnormalities.	Visual inspection.
	Dimension	Within the specified dimensions.	Using calipers.
5	Dielectric Strength	No defects or abnormalities.	Test Voltage :Rated voltagex250% Time : 1 to 5s Charge Current : 50mA max. To apply the test voltge through the Interposer board termination.
6	Insulation Resistance	More than 50Ω · F	Voltage : Rated voltage Time : 1 min Charge Current : 50mA max. To apply the test voltge through the Interposer board termination.
	Capacitance	Within the specified tolerance.	The capacitance should be measured at Standard Temperature at the frequency and voltage shown in the table. Capacitance Frequency Voltage C ≤ 10µF 1±0.1kHz 1.0±0.2Vrms C ≤ 10µF 1±0.1kHz 0.5±0.1Vrms C ≤ 10µF 120±24Hz 0.5±0.1Vrms C > 10µF 120±24Hz 0.5±0.1Vrms Perform a heat treatment at 150+0/-10°C for one hour and then set for 24±2 hour at room temperature. Perform the initial measurement. To apply the test voltge through the Interposer board termination.
8	Dissipation Factor (D.F.)	C8,D7 : 0.1 max.	$\label{eq:constraint} \begin{array}{ c c c c c } \hline The D.F. should be measured at Standard Temperature at the Frequency and voltage shown in the table. \\ \hline \hline Capacitance & Frequency & Voltage \\ \hline C \leq 10 \mu F & 1 \pm 0.1 \text{kHz} & 1.0 \pm 0.2 \text{Vrms} \\ \hline (10V \text{ min.}) & 1 \pm 0.1 \text{kHz} & 1.0 \pm 0.2 \text{Vrms} \\ \hline C \leq 10 \mu F & 1 \pm 0.1 \text{kHz} & 0.5 \pm 0.1 \text{Vrms} \\ \hline C > 10 \mu F & 120 \pm 24 \text{Hz} & 0.5 \pm 0.1 \text{Vrms} \\ \hline \end{array}$
9	Capacitance No bias Temperature Characteristics	C8 : Within ±22% (-55°C to +105°C) D7 : Within +22,-33% (-55°C to +125°C)	The capacitance change should be measured after 5min. at each specified temp.stage. In case of applying voltage, the capacitance change should be measured after 1 more min. • Measurement Voltage ZRB18A C8 1A 106 K ZRB18A C8 1A 106 K only : 0.20±0.05Vrms Test Conditions Step Temperature(°C) Applying voltage(V) 1 25+/-2(for C8, D7) 2 -55+/-3(for C8, D7) 3 25+/-2(for C8, D7) 4 125±3(for D7) 1 105±3(for C8)
10	Adhesive Strength of	No removal of the terminations or other defect should occur.	Perform a heat treatment at 150+0/-10°C for one hour and then set at room temperature for 24±2 hours. Perform the initial measurement. Solder the capacitor on the test jig shown in Fig.3 using
	Termination		an solder. Applying Force(F) : 10N* *5N : ZRB15/18 Applying time : 10±1s



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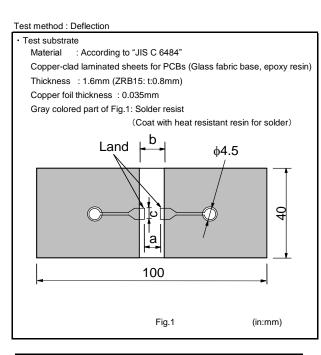
■SPECIFICATIONS AND TEST METHODS

11		m	Specification	Test Method
	Vibration Resistance	Appearance	No defects or abnormalities.	Solder the capacitor on the test jig shown in Fig.3 using
	Resistance	Capacitance	Within the specified tolerance.	Oscillation Frequency : A 10Hz to 55Hz to 10Hz for 1 min
		D.F.	C0 D7 - 0.4 men	Total Amplitude 1.5mm
		D.F.	C8,D7 : 0.1 max.	A period of 2 hours in each of 3 mutually perpendicular directions. (Total 6 h)
12	Deflection Appearance No		No defects or abnormalities.	Test Method : According to Fig1,Fig2 Deflection : 1mm
		Capacitance	Within ±10%	Keeping Time : 5±1s
13	Solderability o	Change	75% of the terminations is to be soldered evenly	Mounting Method : Reflow soldering Test Conditions : solder bath method, method 1
	Interposer boa	rd termination	and continuously.	Solder : Sn-3.0Ag-0.5 Cu solder Solder Temperature : 245±5°C
				Solder remperature . 245±5 C
				Immersion Time : 2±0.5s
	Desistance to	A		
	Resistance to Soldering Heat	Appearance	No defects or abnormalities.	Test Conditions : Reflow method Solder : Sn-3.0Ag-0.5 Cu solder
		Capacitance Change	C8,D7 : Within ±7.5%	Solder Temperature : 255°C ±10°C[Peak Temperature]
		onango		Heat Time of over 200°C : 120s min
		D.F.	C8,D7 : 0.1 max.	Exposure to room temperature : 24±2h
				Pre-heat : Following conditions
				Table1
		I.R.	More than 50Ω · F	Temperature Time 150°C to 160°C 2 min.
				· · · · · · · · · · · · · · · · · · ·
		Dielosteis	No defects	
		Dielectric Strength	No defects.	 Initial measurement Perform a heat treatment at 150+0/-10°C for one hour and then set at roon
				temperature for 24±2 hours. Perform the initial measurement.
15	Sudden Change	Appearance	No defects or abnormalities.	Solder the capacitor on the test jig shown in Fig.3 using
		Capacitance Change	C8,D7 : Within ±7.5%	Total of 5 cycles Step Temp.(°C) Time (min)
		Change		1 Min. 30+3
		D.F.	C8,D7 : 0.1 max.	Operating Temp.+0/-3 Output 2 Room Temp 2 to 3
		0.1.	00,07 : 0.1 max.	3 Max. Operating Temp.+3/-0 30±3
				4 Room Temp 2 to 3
				Exposure to room temperature : 24±2 h
		I.R.	More than 50 $\Omega\cdotF$	- Initial measurement
		I.R.	More than 50Ω · F	Initial measurement Perform a heat treatment at 150+0/-10°C for one hour and then set
				Initial measurement
		I.R. Dielectric Strength	More than 50Ω · F No defects.	Initial measurement Perform a heat treatment at 150+0/-10°C for one hour and then set at room temperature for 24±2 hours.
		Dielectric		Initial measurement Perform a heat treatment at 150+0/-10°C for one hour and then set at room temperature for 24±2 hours.
16	High	Dielectric		Initial measurement Perform a heat treatment at 150+0/-10°C for one hour and then set at room temperature for 24±2 hours. Perform the initial measurement. Temperature : 40±2°C
16	High Temperature High	Dielectric Strength	No defects.	Initial measurement Perform a heat treatment at 150+0/-10°C for one hour and then set at room temperature for 24±2 hours. Perform the initial measurement.
	Temperature High Humidity	Dielectric Strength Appearance	No defects. No defects or abnormalities.	Initial measurement Perform a heat treatment at 150+0/-10°C for one hour and then set at room temperature for 24±2 hours. Perform the initial measurement. Temperature : 40±2°C Humidity : 90 to 95% Time : 500±12h Test Voltage : Rated voltage
	Temperature High	Dielectric Strength Appearance Capacitance	No defects. No defects or abnormalities.	Initial measurement Perform a heat treatment at 150+0/-10°C for one hour and then set at room temperature for 24±2 hours. Perform the initial measurement. Temperature : 40±2°C Humidity : 90 to 95% Time : 500±12h Test Voltage : Rated voltage Charge Current : 50mA.
	Temperature High Humidity	Dielectric Strength Appearance Capacitance Change	No defects. No defects or abnormalities. C8,D7 : Within ±12.5%	Initial measurement Perform a heat treatment at 150+0/-10°C for one hour and then set at room temperature for 24±2 hours. Perform the initial measurement. Temperature : 40±2°C Humidity : 90 to 95% Time : 500±12h Test Voltage : Rated voltage Charge Current : 50mA. Initial measurement
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	Temperature High Humidity	Dielectric Strength Appearance Capacitance Change D.F.	No defects. No defects or abnormalities. C8,D7 : Within ±12.5% C8,D7 : 0.2max.	Initial measurement Perform a heat treatment at 150+0/-10°C for one hour and then set at room temperature for 24±2 hours. Perform the initial measurement. Temperature : 40±2°C Humidity : 90 to 95% Time : 500±12h Test Voltage : Rated voltage Charge Current : 50mA. Initial measurement Perform a heat treatment at 150+0/-10°C for one hour and then let sit for 24±2 hours at room temperature. Perform the initial measurement. Measurement after test
	Temperature High Humidity	Dielectric Strength Appearance Capacitance Change D.F.	No defects. No defects or abnormalities. C8,D7 : Within ±12.5% C8,D7 : 0.2max.	Initial measurement Perform a heat treatment at 150+0/-10°C for one hour and then set at room temperature for 24±2 hours. Perform the initial measurement. Temperature : 40±2°C Humidity : 90 to 95% Time : 500±12h Test Voltage : Rated voltage Charge Current : 50mA. Initial measurement Perform a heat treatment at 150+0/-10°C for one hour and then let sit for 24±2 hours at room temperature. Perform the initial measurement. Measurement after test
	Temperature High Humidity (Steady)	Dielectric Strength Appearance Capacitance Change D.F.	No defects. No defects or abnormalities. C8,D7 : Within ±12.5% C8,D7 : 0.2max. More than 12.5Ω · F	 Initial measurement Perform a heat treatment at 150+0/-10°C for one hour and then set at room temperature for 24±2 hours. Perform the initial measurement. Temperature : 40±2°C Humidity : 90 to 95% Time : 500+12h Test Voltage : Rated voltage Charge Current : 50mA. Initial measurement Perform a heat treatment at 150+0/-10°C for one hour and then let sit for 24±2 hours at room temperature. Perform the initial measurement. Initial measurement Perform the initial measurement. Perform the initial measurement. Initial measurement Perform the initial measurement. Perform the initial measurement. Perform the initial measurement. Indexsurement after test Perform a heat treatment and then let sit for 24+/-2 hours at room temperature. Perform a neat treatment and then let sit for 24+/-2 hours at room temperature.
	Temperature High Humidity	Dielectric Strength Appearance Capacitance Change D.F. I.R.	No defects. No defects or abnormalities. C8,D7 : Within ±12.5% C8,D7 : 0.2max. More than 12.5Ω · F	 Initial measurement Perform a heat treatment at 150+0/-10°C for one hour and then set at room temperature for 24±2 hours. Perform the initial measurement. Temperature : 40±2°C Humidity : 90 to 95% Time : 500±12h Test Voltage : Rated voltage Charge Current : 50mA. Initial measurement Perform a heat treatment at 150+0/-10°C for one hour and then let sit for 24±2 hours at room temperature. Perform the initial measurement. Measurement after test Perform a heat treatment and then let sit for 24+/-2 hours at room temperature the measure. Temperature : Maximum operating temperature ±3°C Time : 1000±12h
	Temperature High Humidity (Steady)	Dielectric Strength Appearance Capacitance Change D.F.	No defects. No defects or abnormalities. C8,D7 : Within ±12.5% C8,D7 : 0.2max. More than 12.5Ω · F	Initial measurement Perform a heat treatment at 150+0/-10°C for one hour and then set at room temperature for 24±2 hours. Perform the initial measurement. Temperature : 40±2°C Humidity : 90 to 95% Time : 500±12h Test Voltage : Rated voltage Charge Current : 50mA. Initial measurement Perform a heat treatment at 150+0/-10°C for one hour and then let sit for 24±2 hours at room temperature. Perform the initial measurement. Measurement after test Perform a heat treatment and then let sit for 24+/-2 hours at room temperatur then measure. Temperature : Maximum operating temperature ±3°C
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	Temperature High Humidity (Steady)	Dielectric Strength Appearance Capacitance Change D.F. I.R. Appearance Capacitance	No defects. No defects or abnormalities. C8,D7 : Within ±12.5% C8,D7 : 0.2max. More than 12.5Ω · F	Initial measurement Perform a heat treatment at 150+0/-10°C for one hour and then set at room temperature for 24±2 hours. Perform the initial measurement. Temperature : 40±2°C Humidity : 90 to 95% Time : 500±12h Test Voltage : Rated voltage Charge Current : 50mA. Initial measurement Perform a heat treatment at 150+0/-10°C for one hour and then let sit for 24±2 hours at room temperature. Perform the initial measurement. Measurement after test Perform a heat treatment and then let sit for 24+/-2 hours at room temperature then measure. Temperature : Maximum operating temperature ±3°C Time : 1000±12h Test Voltage : Rated voltagex150%
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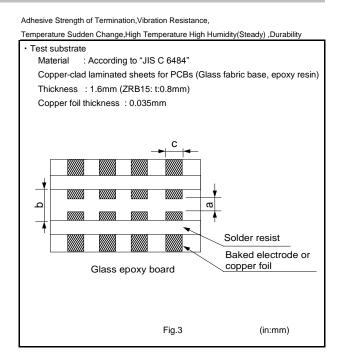


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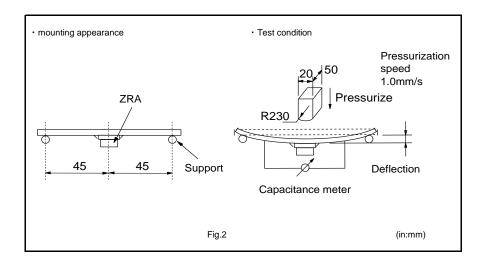
SPECIFICATIONS AND TEST METHODS



Turne	Dimension (mm)		
туре	а	b	С
ZRB18	1.0	3.0	1.2



Turne	Dimension (mm)		
Туре	а	b	C
ZRB18	1.0	3.0	1.2





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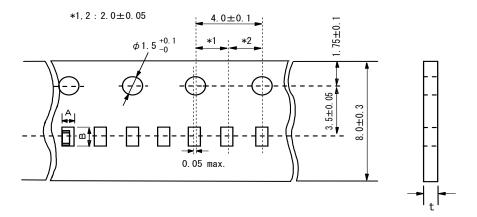
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Ζ	R	В	T	y	ре

- 1.Tape Carrier Packaging(Packaging Code:D/L)
- 1.1 Minimum Quantity(pcs./reel)

		φ180mm reel		
T	уре	Paper Tape	Plastic Tape	
		Code:D	Code:L	
ZRB15	Х	8000		
ZRB18	А		3000	

1.2 Dimensions of Tape (1)ZRB15

(in:mm)



Code	ZRB15	
A *3	0.8	
B *3	1.3	*3 Nominal value
t *3	0.95	

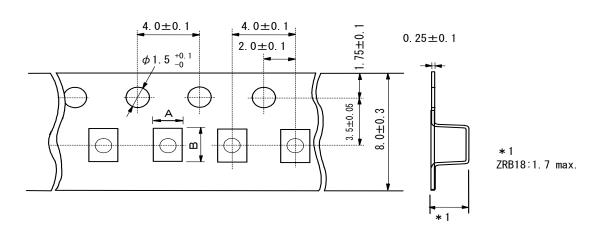


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Package
ZRB Type

(2)ZRB18

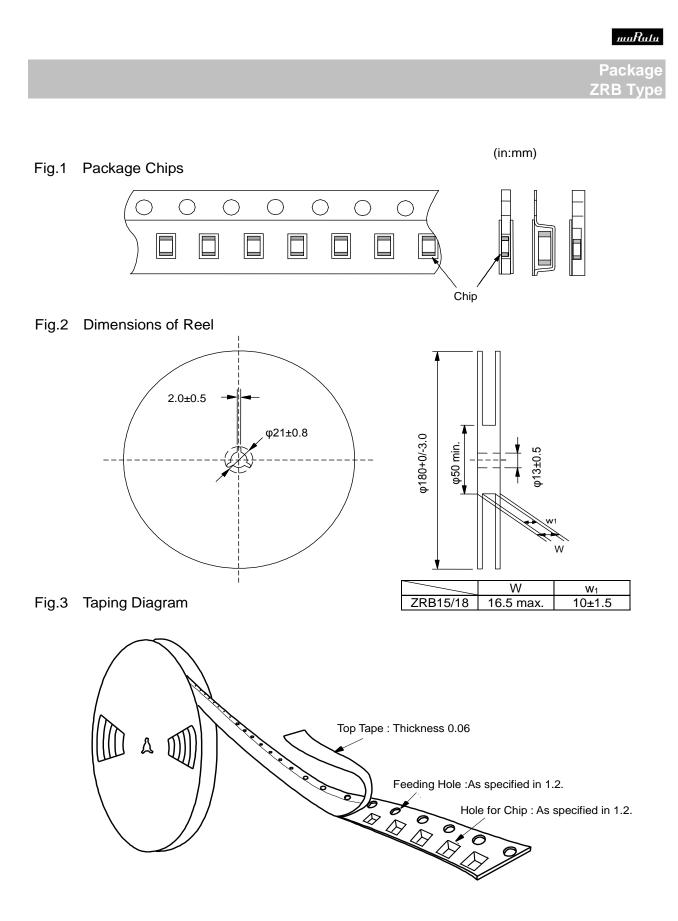
(in:mm)



Code	ZRB18
A *2	1.1
B *2	2.0

*2 Nominal value

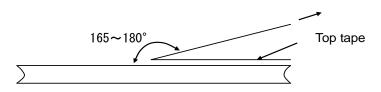






maRata Package 7RB1 1.3 Tapes for capacitors are wound clockwise shown in Fig.3. (The sprocket holes are to the right as the tape is pulled toward the user.) 1.4 Part of the leader and part of the vacant section are attached as follows. (in:mm) **Tail vacant Section** Chip-mounting Unit Leader vacant Section Leader Unit (Top Tape only) Direction of Feed 160 min. 190 min. 210 min.

- 1.5 Accumulate pitch : 10 of sprocket holes pitch = 40 ± 0.3 mm
- 1.6 Chip in the tape is enclosed by top tape and bottom tape as shown in Fig.1.
- 1.7 The top tape and base tape are not attached at the end of the tape for a minimum of 5 pitches.
- 1.8 There are no jointing for top tape and bottom tape.
- 1.9 There are no fuzz in the cavity.
- 1.10 Break down force of top tape : 5N min. Break down force of bottom tape : 5N min. (Only a bottom tape existence)
- 1.11 Reel is made by resin and appeaser and dimension is shown in Fig 2. There are possibly to change the material and dimension due to some impairment.
- 1.12 Peeling off force : 0.1 to 0.6N in the direction as shown below.



1.13 Label that show the customer parts number, our parts number, our company name, inspection number and quantity, will be put in outside of reel.





Limitation of use

Please contact our sales representatives or product engineers before using our products for the applications listed below which require of our products for other applications than specified in this product.
①Aircraft equipment
②Aerospace equipment
③Undersea equipment
④Power plant control equipment
⑤Medical equipment
⑥Transportation equipment(vehicles,trains,ships,etc.)
⑦Traffic signal equipment
⑧Data-processing equipment
⑩Application of similar complexity and/or requirements to the applications listed in the above

Storage and Operation condition

- 1. The performance of MLCC on Interposer (ZRB series) may be affected by the storage conditions.
- 1-1. Store capacitors in the following conditions: Temperature of +5°C to +40°C and a Relative Humidity of 20% to 70%.
- (1) Sunlight, dust, rapid temperature changes, corrosive gas atmosphere or high temperature and humidity conditions during storage may affect the solderability and the packaging performance Please use product within six months of receipt.
- (2) Please confirm solderability before using after six months.Store the capacitors without opening the original bag.Even if the storage period is short, do not exceed the specified atmospheric conditions.
- 1-2. Corrosive gas can react with the termination (external) electrodes or lead wires of capacitors, and result in poor solderability. Do not store the capacitors in an atmosphere consisting of corrosive gas (e.g., hydrogen sulfide, sulfur dioxide, chlorine, ammonia gas etc.).
- 1-3. Due to moisture condensation caused by rapid humidity changes, or the photochemical change caused by direct sunlight on the terminal electrodes and/or the resin/epoxy coatings, the solderability and electrical performance may deteriorate. Do not store capacitors under direct sunlight or in high huimidity conditions





Rating

1.Temperature Dependent Characteristics

- 1. The electrical characteristics of the capacitor can change with temperature.
- 1-1. For capacitors having larger temperature dependency, the capacitance may change with temperature changes.

The following actions are recommended in order to insure suitable capacitance values.

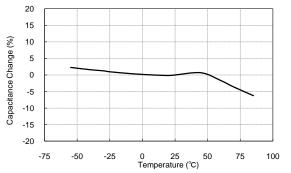
- (1) Select a suitable capacitance for the operating temperature range.
- (2) The capacitance may change within the rated temperature.

When you use a high dielectric constant type capacitors in a circuit that needs a tight (narrow) capacitance tolerance.

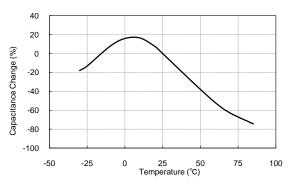
Example: a time constant circuit., please carefully consider the characteristics of these capacitors, such as their aging, voltage, and temperature characteristics.

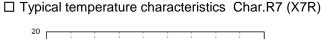
And check capacitors using your actual appliances at the intended environment and operating conditions.

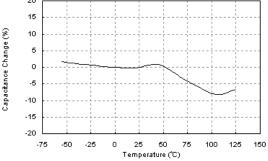
□ Typical temperature characteristics Char.R6 (X5R)











2.Measurement of Capacitance

- 1. Measure capacitance with the voltage and the frequency specified in the product specifications.
- 1-1. The output voltage of the measuring equipment may decrease when capacitance is high occasionally. Please confirm whether a prescribed measured voltage is impressed to the capacitor.
- 1-2. The capacitance values of high dielectric constant type capacitors change depending on the AC voltage applied.

Please consider the AC voltage characteristics when selecting a capacitor to be used in a AC circuit.





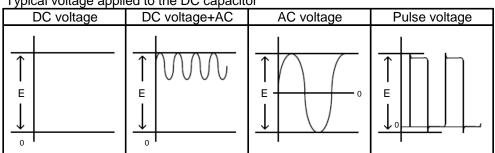


3.Applied Voltage

- 1. Do not apply a voltage to the capacitor that exceeds the rated voltage as called-out in the specifications.
- 1-1. Applied voltage between the terminals of a capacitor shall be less than or equal to the rated voltage.
- (1) When AC voltage is superimposed on DC voltage, the zero-to-peak voltage shall not exceed the rated DC voltage.

When AC voltage or pulse voltage is applied, the peak-to-peak voltage shall not exceed the rated DC voltage.

(2) Abnormal voltages (surge voltage, static electricity, pulse voltage, etc.) shall not exceed the rated DC voltage.



Typical voltage applied to the DC capacitor

(E : Maximum possible applied voltage.)

1-2. Influence of overvoltage

Overvoltage that is applied to the capacitor may result in an electrical short circuit caused by the breakdown of the internal dielectric layers .

The time duration until breakdown depends on the applied voltage and the ambient temperature.

4. Applied Voltage and Self-heating Temperature

- 1. When the capacitor is used in a high-frequency voltage, pulse voltage, application, be sure to take into account self-heating may be caused by resistant factors of the capacitor.
- 1-1. The load should be contained to the level such that when measuring at atomospheric temperature of 25°C, the product's self-heating remains below 20°C and surface temperature of the capacitor in the actual circuit remains wiyhin the maximum operating temperature.



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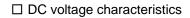


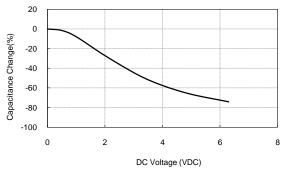
5. DC Voltage and AC Voltage Characteristic

1. The capacitance value of a high dielectric constant type capacitor changes depending on the DC voltage applied.

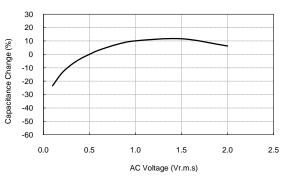
Please consider the DC voltage characteristics when a capacitor is selected for use in a DC circuit.

- 1-1. The capacitance of ceramic capacitors may change sharply depending on the applied voltage. (See figure) Please confirm the following in order to secure the capacitance.
- (1) Whether the capacitance change caused by the applied voltage is within the range allowed or not.
- (2) In the DC voltage characteristics, the rate of capacitance change becomes larger as voltage increases.
 Even if the applied voltage is below the rated voltage.
 When a high dielectric constant type capacitor is in a circuit that needs a tight (narrow) capacitance tolerance.
 Example: a time constant circuit., please carefully consider the characteristics of these capacitors, such as their aging, voltage, and temperature characteristics.
 And check capacitors using your actual appliances at the intended environment and operating conditions.





2. The capacitance values of high dielectric constant type capacitors change depending on the AC voltage applied. Please consider the AC voltage characteristics when selecting a capacitor to be used in a AC circuit.



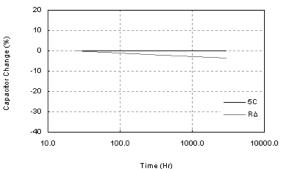
□ AC voltage characteristics

6. Capacitance Aging

1. The high dielectric constant type capacitors have the characteristic in which the capacitance value decreases with passage of time.

When you use a high dielectric constant type capacitors in a circuit that needs a tight (narrow) capacitance tolerance. Example: a time constant circuit., please carefully consider the characteristics of these capacitors, such as their aging, voltage, and temperature characteristics.

And check capacitors using your actual appliances at the intended environment and operating conditions.





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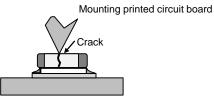


7.Vibration and Shock

- 1. Please confirm the kind of vibration and/or shock, its condition, and any generation of resonance. Please mount the capacitor so as not to generate resonance, and do not allow any impact on the terminals.
- 2. Mechanical shock due to falling may cause damage or a crack in the dielectric material of the capacitor. Do not use a fallen capacitor because the quality and reliability may be deteriorated.



3. When printed circuit boards are piled up or handled, the corners of another printed circuit board should not be allowed to hit the capacitor in order to avoid a crack or other damage to the capacitor.



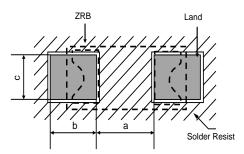
Soldering and Mounting

1.Mounting for MLCC on Interposer (ZRB series)

Please refer to the land dimensions in Table 1 for ZRB series.

(1)Recommended Land Dimensions

Table1 Land Dimensions					
Dimensions Part Number	L×W	а	b	С	
ZRB15	1.0×0.5	0.4~0.6	0.4~0.5	0.5~0.7	
ZRB18	1.6×0.8	0.7~0.9	0.7~0.8	0.8~1.0	
				(in mm	



If distance between parts is too short, there is risk to cause electrical short. Please confirm the mounting pitch (distance between centers of parts) has 1.275mm or more. (ZRB18 only) Please confirm the suitable mounting condition by evaluating of the actual SET / PCB.

JEMCGC-02188B



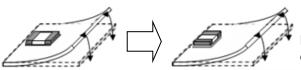




2.Mounting Position

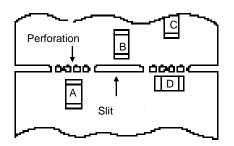
- 1. Confirm the best mounting position and direction that minimizes the stress imposed on the capacitor during flexing or bending the printed circuit board.
- 1-1.Choose a mounting position that minimizes the stress imposed on the chip during flexing or bending of the board.

[Component Direction]



Locate chip horizontal to the direction in which stress acts

[Chip Mounting Close to Board Separation Point]



Chip arrangement Worst A-C-(B~D) Best

3.Information before mounting

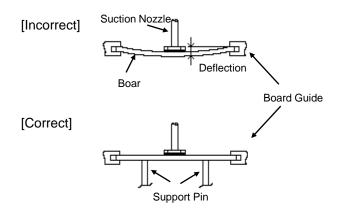
- 1. Do Not re-use capacitors that were removed from the equipment.
- 2. Confirm capacitance characteristics under actual applied voltage.
- 3. Confirm the mechanical stress under actual process and equipment use.
- 4. Confirm the rated capacitance, rated voltage and other electrical characteristics before assembly.
- 5. Prior to use, confirm the Solderability for the capacitors that were in long-term storage.
- 6. Prior to measuring capacitance, carry out a heat treatment for capacitors that were in long-term storage.
- 7. The use of Sn-Zn based solder will deteriorate the reliability of the MLCC. Please contact our sales representative or product engineers on the use of Sn-Zn based solder in advance.





4.Maintenance of the Mounting (pick and place) Machine

- 1. To adjust the inspection tolerance for automated appearance sorting machine of mounting position, because ZRB series are easier to shift the mounting position than standard MLCC.
- 2. To check the overturn and reverse of ZRB chip.
- 3. To control mounting speed carefully, because ZRB chip is heavier than standard MLCC.
- 4. Make sure that the following excessive forces are not applied to the capacitors.
- 4-1. In mounting the capacitors on the printed circuit board, any bending force against them shall be kept to a minimum to prevent them from any bending damage or cracking. Please take into account the following precautions and recommendations for use in your process.
- (1) Adjust the lowest position of the pickup nozzle so as not to bend the printed circuit board.
- (2) Adjust the nozzle pressure within a static load of 1N to 3N during mounting.



5.Dirt particles and dust accumulated between the suction nozzle and the cylinder inner wall prevent the nozzle from moving smoothly. This imposes greater force upon the chip during mounting, causing cracked chips. Also the locating claw, when worn out, imposes uneven forces on the chip when positioning, causing cracked chips. The suction nozzle and the locating claw must be maintained, checked and replaced periodically.



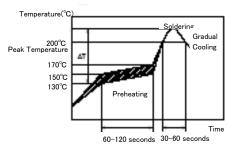




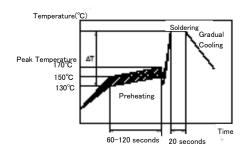
5-1.Reflow Soldering

- 1. When sudden heat is applied to the components, the mechanical strength of the components will decrease because a sudden temperature change causes deformation inside the components. In order to prevent mechanical damage to the components, preheating is required for both the components and the PCB board. Preheating conditions are shown in table 1. It is required to keep the temperature differential between the solder and the components surface (ΔT) as small as possible.
- Solderability of Tin plating termination chips might be deteriorated when a low temperature soldering profile where the peak solder temperature is below the melting point of Tin is used. Please confirm the Solderability of Tin plated termination chips before use.
- 3. When components are immersed in solvent after mounting be sure to maintain the temperature difference (ΔT) between the component and the solvent within the range shown in the table 1.

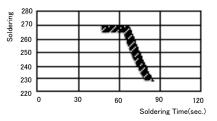
[Standard Conditions for Reflow Soldering] Infrared Reflow



Vapor Reflow



[Allowable Soldering Temperature and Time]



In case of repeated soldering, the accumulated soldering time must be within the range shown above.

shown in the table 1.

Part Number	Temperature Differential
ZRB15/ZRB18	ΔT≦190°C

Recommended Conditions

	Pb-Sn	Lead Free Solder	
	Infrared Reflow	Vapor Reflow	Lead Tree Solder
Peak Temperature	230~250°C	230~240°C	240~260°C
Atmosphere	Air	Air	Air or N ₂

Lead Free Solder: Sn-3.0Ag-0.5Cu

5-2.Correction with a Soldering Iron

Correction with a soldering iron for ZRB chip may cause loss suppress acoustic noise, because the solder amount become excessive. Do not correct with a soldering iron for ZRB series.



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6.Washing

Excessive ultrasonic oscillation during cleaning can cause the PCBs to resonate, resulting in cracked chips or broken solder joints. Take note not to vibrate PCBs.

7.Electrical Test on Printed Circuit Board

- 1. Confirm position of the support pin or specific jig, when inspecting the electrical performance of a capacitor after mounting on the printed circuit board.
- 1-1. Avoid bending printed circuit board by the pressure of a test pin, etc. The thrusting force of the test probe can flex the PCB, resulting in cracked chips or open solder joints. Provide support pins on the back side of the PCB to prevent warping or flexing.
- 1-2. Avoid vibration of the board by shock when a test pin contacts a printed circuit board.

□ Not recommended

□ Recommended





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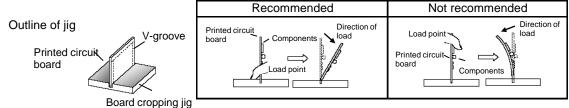
8.Printed Circuit Board Cropping

- 1. After mounting a capacitor on a printed circuit board, do not apply any stress to the capacitor that is caused by bending or twisting the board.
- 1-1. In cropping the board, the stress as shown right may cause the capacitor to crack. Try not to apply this type of stress to a capacitor.



- 2. Check of the cropping method for the printed circuit board in advance.
- 2-1. Printed circuit board cropping shall be carried out by using a jig or an apparatus to prevent the mechanical stress which can occur to the board.
 - (1) Example of a suitable jig

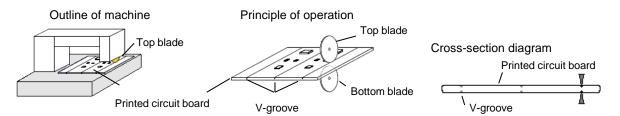
Recommended example: the board should be pushed as close to the near the cropping jig as possible and from the back side of board in order to minimize the compressive stress applied to capacitor. Not recommended example* when the board is pushed at a point far from the cropping jig and from the front side of board as below, the capacitor may form a crack caused by the tensile stress applied to capacitor.



(2) Example of a suitable machine

An outline of a printed circuit board cropping machine is shown as follows. Along the lines with the V-grooves on printed circuit board, the top and bottom blades are aligned to one another when cropping the board.

The misalignment of the position between top and bottom blades may cause the capacitor to crack.



Recommended	Not recommended			
Recommended	Top-bottom misalignment	Left-right misalignment	Front-rear misalignment	
Top blade	Top blade	Top blade	Top blade	
Bottom blade	Bottom blade	Bottom blade	Bottom blade	







Others

1. Under Operation of Equipment

- 1-1. Do not touch a capacitor directly with bare hands during operation in order to avoid the danger of a electric shock.
- 1-2. Do not allow the terminals of a capacitor to come in contact with any conductive objects (short-circuit). Do not expose a capacitor to a conductive liquid, inducing any acid or alkali solutions.
- 1-3. Confirm the environment in which the equipment will operation is under the specified conditions. Do not use the equipment under the following environment.
 - (1) Being spattered with water or oil.
 - (2) Being exposed to direct sunlight.
 - (3) Being exposed to Ozone, ultraviolet rays or radiation.
 - (4) Being exposed to toxic gas (e.g., hydrogen sulfide, sulfur dioxide, chlorine, ammonia gas etc.)
 - (5) Any vibrations or mechanical shocks exceeding the specified limits.
 - (6) Moisture condensing environments.
- 1-4. Use damp proof countermeasures if using under any conditions that can cause condensation.

2. Others

- 2-1. In an Emergency
- (1) If the equipment should generate smoke, fire or smell, immediately turn off or unplug the equipment. If the equipment is not turned off or unplugged, the hazards may be worsened by supplying continuous power.
- (2) In this type of situation, do not allow face and hands to come in contact with the capacitor or burns may be caused by the capacitors high temperature.
- 2-2. Disposal of waste

When capacitors are disposed, they must be burned or buried by the industrial waste vender with the appropriate licenses.

2-3. Circuit Design

ZRB series in this product specification are not safety recognized products.

2-4. Remarks

Failure to follow the cautions may result, worst case, in a short circuit and smoking when the product is used.

The above notices are for standard applications and conditions. Contact us when the products are used in special mounting conditions.

Select optimum conditions for operation as they determine the reliability of the product after assembly. The data herein are given in typical values, not guaranteed ratings.







Rating

1.Operating Temperature

- 1. The operating temperature limit depends on the capacitor.
- 1-1.Do not apply temperatures exceeding the upper operating temperature.

It is necessary to select a capacitor with a suitable rated temperature which will cover the operating temperature range.

Also it is necessary to consider the temperature distribution in equipment and the seasonal temperature variable factor.

1-2.Consider the self-heating of the capacitor The surface temperature of the capacitor shall be the upper operating temperature or less when including the self-heating factors.

2.Atmosphere surroundings (gaseous and liquid)

- 1. Restriction on the operating environment of capacitors.
- 1-1. The capacitor, when used in the above, unsuitable, operating environments may deteriorate due to the corrosion of the terminations and the penetration of moisture into the capacitor.
- 1-2. The same phenomenon as the above may occur when the electrodes or terminals of the capacitor are subject to moisture condensation.
- 1-3. The deterioration of characteristics and insulation resistance due to the oxidization or corrosion of terminal electrodes may result in breakdown when the capacitor is exposed to corrosive or volatile gases or solvents for long periods of time.

3.Piezo-electric Phenomenon

 When using high dielectric constant type capacitors in AC or pulse circuits, the capacitor itself vibrates at specific frequencies and noise may be generated. Moreover, when the mechanical vibration or shock is added to capacitor, noise may occur.





Soldering and Mounting

1.PCB Design

- 1. Notice for Pattern Forms
- 1-1.There is a possibility of chip crack caused by PCB expansion/contraction with heat. Because stress for chip is different depend on PCB material and structure.Especially metal PCB such as alumina has a greater risk of chip crack because of large difference of thermal expansion coefficient.

2.Washing

- 1. Please evaluate a capacitor by actual cleaning equipment and condition surely for confirming the quality and select the applicable solvent.
- 2. Unsuitable cleaning solvent may leave residual flux, other foreign substances, causing deterioration of electrical characteristics and the reliability of the capacitors.
- 3. Select the proper cleaning conditions.
- 3-1. Improper cleaning conditions (excessive or insufficient) may result in the deterioration of the performance of the capacitors.

3.Coating

1. Loss suppress acoustic noise may be caused in ZRB chip due to the resin during curing process. Please contact our sales representative or product engineers on the apply to resin during curing process.







Others

1.Transportation

- 1. The performance of a capacitor may be affected by the conditions during transportation.
- 1-1. The capacitors shall be protected against excessive temperature, humidity and mechanical force during transportation.
- (1) Climatic condition
 - low air temperature : -40°C
 - change of temperature air/air : -25°C/+25°C
 - low air pressure : 30 kPa
 - change of air pressure : 6 kPa/min
- (2) Mechanical condition

Transportation shall be done in such a way that the boxes are not deformed and forces are not directly passed on to the inner packaging.

- 1-2. Do not apply excessive vibration, shock, and pressure to the capacitor.
- (1) When excessive mechanical shock or pressure is applied to a capacitor, chipping or cracking may occur in the ceramic body of the capacitor.
- (2) When a sharp edge of an air driver, a soldering iron, tweezers, a chassis, etc. impacts strongly on the surface of capacitor, the capacitor may crack and short-circuit.
- 1-3. Do not use a capacitor to which excessive shock was applied by dropping etc. The capacitor dropped accidentally during processing may be damaged.





- 1.Please make sure that your product has been evaluated in view of your specifications with our product being mounted to your product.
- 2. Your are requested not to use our product deviating from this product specification.
- 3.We consider it not appropriate to include any terms and conditions with regard to the business transaction in the product specifications, drawings or other technical documents. Therefore, if your technical documents as above include such terms and conditions such as warranty clause, product liability clause, or intellectual property infringement liability clause, they will be deemed to be invalid.